

Erratum to “Modeling Avalanche Induced Degradation for 4H-SiC Power MOSFETs”

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In article [1], the affiliations were not correct in the first footnote. The correct footnote should read as follows:

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REFERENCE

- [1] J. Wei, S. Liu, X. Zhang, W. Sun, and A. Q. Huang, “Modeling avalanche induced degradation for 4H-SiC power MOSFETs,” *IEEE Trans. Power Electron.*, vol. 35, no. 11, pp. 11299–11303, Nov. 2020.

Manuscript received August 10, 2020; accepted August 10, 2020. Date of current version September 22, 2020.

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Digital Object Identifier 10.1109/TPEL.2020.3016196